

AMENDMENTS TO THE CLAIMS

1. (Currently amended) A semiconductor test apparatus that tests the operation of a semiconductor based on comprising:

a memory for storing a plurality of pattern data comprising: files each containing data;

a counter device that counts the number of times pattern the data is used for of each of said pattern files is used; and

a control unit that produces a pattern file use frequency table showing the relationship between each of said pattern files and said number of times the said pattern files are used, and stores this pattern file use frequency table in the said memory.

2. (Currently amended) A semiconductor test apparatus according to claim 1 wherein said counting counter device counts the number of times each said pattern data file of said plurality of pattern files is used in a set of test tests for a predetermined number of semiconductors.

3. (Currently amended) A semiconductor test apparatus according to claim 1, wherein said control unit rearrange the rearranges said plurality of pattern files in descending order of frequency of use based on said pattern file use frequency table after producing said pattern file use frequency table.

4. (Currently amended) A semiconductor test apparatus according to claim 1, wherein said control unit deletes the pattern files in ascending order of frequency of use in the case that the capacity of the an executive memory is insufficient when transferring said pattern files to the executive memories memory.

5. (Currently amended) A control method of the for a semiconductor test apparatus that tests the operation of a semiconductor based on a plurality of pattern files each containing pattern data, comprising the steps of:

counting the number of times said pattern data ~~is used for~~ of each said pattern file is used, and

preparing a pattern file use frequency table that shows the relationship between each pattern file of said plurality of pattern files and the number of times these files are each said pattern file is used, and

storing this pattern file use frequency table in ~~the~~ a memory.

6. (Currently amended) A control method ~~of the~~ for a semiconductor test apparatus according to claim 5, wherein, in said counting step, the number of times said pattern data in each of said plurality of pattern files is used in a set of test tests for a predetermined number of semiconductors is counted.

7. (Currently amended) A control method ~~of the~~ for a semiconductor test apparatus according to claim 5, wherein said storing step stores the said plurality of pattern files in descending order of frequency of use based on said pattern file use frequency table after producing said pattern file use frequency table is prepared.

8. (Currently amended) A control method ~~of the~~ for a semiconductor test apparatus according to claim 5, wherein said storage storing step deletes the pattern files from said plurality of pattern files in ascending order of frequency of use in the case that the capacity of the executive said memory is insufficient when transferring said plurality of pattern files to the executive memories said memory.